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(54) Title: METROLOGY SAMPLING PLANS FOR ONLY OUT OF SPECIFICATION DETECTION

(57) Abstract: Methods and systems for determining information for a specimen are provided. One method includes generating a sampling plan for only out of specification detection of a characteristic of specimens in a metrology process. The method also includes generating output for the specimens by performing the metrology process on the specimens with the generated sampling plan. In addition, the method includes determining the characteristic of the specimen based on the generated output and detecting if the characteristic of one or more of the specimens is out of specification based on the determined characteristic of the specimens. The embodiments described herein are particularly suitable for overlay metrology with substantially sparse sampling plans configured for only out of specification detection of the overlay.

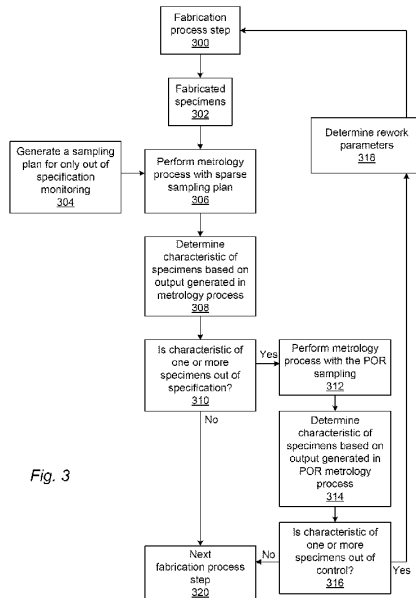


Fig. 3

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